July 1998



SEMICONDUCTOR TM

FDP6035AL/FDB6035AL

N-Channel Logic Level PowerTrench[™] MOSFET

General Description

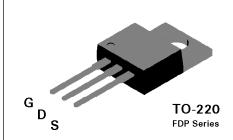
This N-Channel Logic Level MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

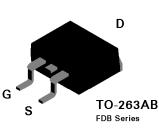
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{_{\text{DS}(on)}}$ specifications.

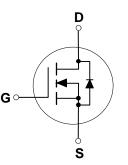
The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 48A, 30 V. $R_{DS(ON)} = 0.0125 \Omega @ V_{GS} = 10 V, R_{DS(ON)} = 0.017 \Omega @ V_{GS} = 4.5 V.$
- Critical DC electrical parameters specified at elevated temperature.
- Rugged internal source-drain diode can eliminate the need for an external Zener diode transient suppressor.
- High performance trench technology for extremely low $R_{\text{DS(ON)}}$.
- 175°C maximum junction temperature rating.







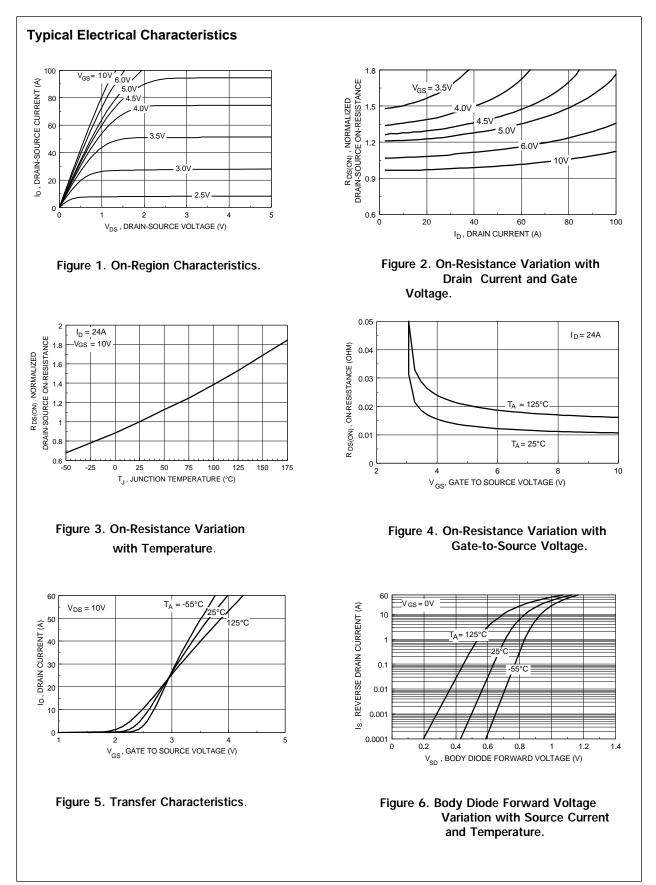
Absolute Maximum Ratings $T_c = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	FDP6035AL	FDB6035AL	Units
V _{DSS}	Drain-Source Voltage	30		V
V _{GSS}	Gate-Source Voltage	±20		V
I _D	Drain Current - Continuous (Note 1)	48		Α
	- Pulsed (Note 1)	150)	
P _D	Total Power Dissipation @ $T_c = 25^{\circ}C$	58		W
	Derate above 25°C	0.4		W/°C
T _J ,T _{STG}	Operating and Storage Temperature Range	-65 to 175		°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	275		°C
THERMA	L CHARACTERISTICS			
R _{ejc}	Thermal Resistance, Junction-to-Case	2.6		°C/W
R _{øja}	Thermal Resistance, Junction-to-Ambient	62.5		°C/W

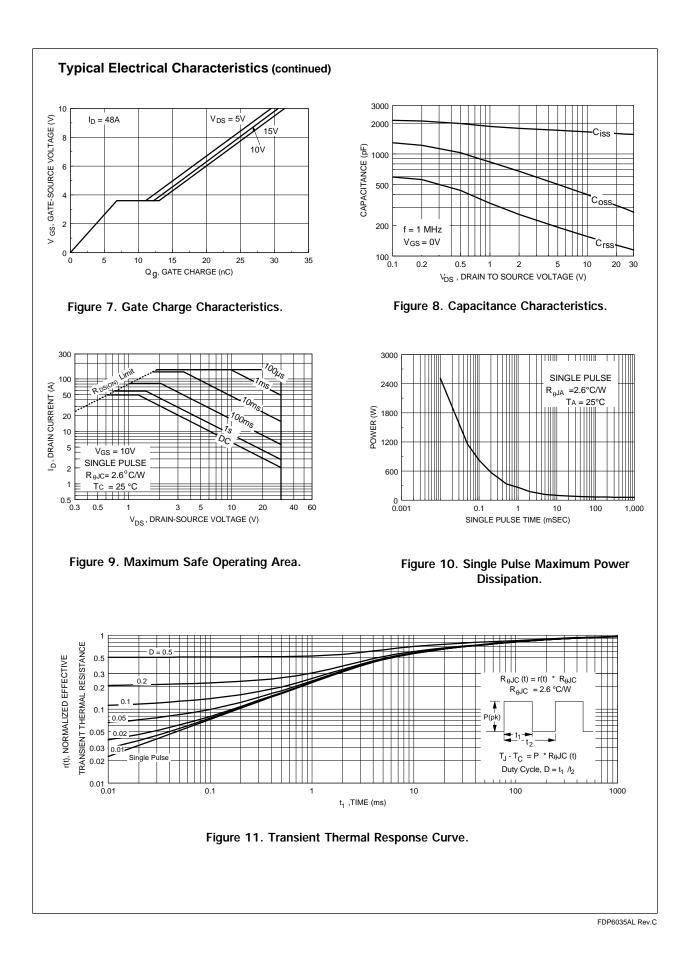
© 1998 Fairchild Semiconductor Corporation

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
DRAIN-SOU	IRCE AVALANCHE RATINGS (Note 1)					
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 15 \text{ V}, \text{ I}_{D} = 48 \text{ A}$			130	mJ
AR	Maximum Drain-Source Avalanche Current				48	Α
OFF CHAR	ACTERISTICS					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$	30			V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_D = 250 \mu\text{A}$, Referenced to $25 ^{\circ}\text{C}$		22		mV/°C
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 24 V, V_{GS} = 0 V$			1	μA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 20 V, V_{DS} = 0 V$			100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
ON CHARA	CTERISTICS (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 250 \mu {\rm A}$	1	1.5	3	V
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold Voltage Temp.Coefficient	$I_{\rm D}$ = 250 µA, Referenced to 25 °C		-5		mV/ºC
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 24 \text{ A}$ $T_{J} = 125^{\circ}\text{C}$		0.011	0.0125	Ω
				0.017	0.021	
		$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 20 \text{ A}$		0.015	0.017	
D(on)	On-State Drain Current	V _{GS} = 10 V, V _{DS} = 10 V	48			Α
9 _{FS}	Forward Transconductance	$V_{\rm DS} = 10 \text{ V}, I_{\rm D} = 24 \text{ A}$		33		S
DYNAMIC C	CHARACTERISTICS					
C _{iss}	Input Capacitance	$V_{DS} = 15 V, V_{GS} = 0 V,$ f = 1.0 MHz		1650		pF
C _{oss}	Output Capacitance			365		pF
C _{rss}	Reverse Transfer Capacitance			170		pF
	CHARACTERISTICS (Note 1)	-				
D(on)	Turn - On Delay Time	$V_{DD} = 15 \text{ V}, \text{ I}_{D} = 1 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		10	18	nS
t T	Turn - On Rise Time			12	22	nS
D(off)	Turn - Off Delay Time			35	56	nS
t,	Turn - Off Fall Time			10	18	nS
Q _g	Total Gate Charge	$V_{DS} = 15 V$, $I_{D} = 48 A$ $V_{GS} = 5 V$		17	23	nC
Q _{gs}	Gate-Source Charge			6.2		nC
Q_{gd}	Gate-Drain Charge			6.8		nC
	IRCE DIODE CHARACTERISTICS		1	1	1	T
s	Maximum Continuous Drain-Source Diode Forward Current (Note 1)				48	A
SM	Maximum Pulsed Drain-Source Diode Forward	Current (Note 1)			150	A
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 24 A$ (Note1)		1.05	1.3	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 V, I_F = 30 A$		23	40	ns
lrr	Reverse Recovery Current	$dI_{F}/dt = 100 \text{ A}/\mu\text{s}$		0.74	1.3	A

1. Pulse Test: Pulse Width \leq 300 µs, Duty Cycle \leq 2.0%.



FDP6035AL Rev.C



TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEx™ Bottomless™ CoolFET™ CROSSVOLT™ DenseTrench™ DOME™ **EcoSPARK™** E²CMOS[™] EnSigna™ FACT™ FACT Quiet Series™ FAST ® FASTr™ FRFET™ GlobalOptoisolator[™] POP[™] GTO™ HiSeC™ ISOPLANAR™ LittleFET™ MicroFET™ MicroPak™ MICROWIRE™

OPTOLOGIC™ OPTOPLANAR™ PACMAN™ Power247™ PowerTrench[®] QFET™ QS™ QT Optoelectronics[™] Quiet Series[™] SILENT SWITCHER®

SMART START™ VCX™ STAR*POWER™ Stealth™ SuperSOT[™]-3 SuperSOT[™]-6 SuperSOT[™]-8 SyncFET™ TinyLogic™ TruTranslation[™] UHC™ UltraFET[®]

STAR*POWER is used under license

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY. FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.

2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.	
First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.	
Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes a any time without notice in order to improve design.	
Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.	
	In Design First Production Full Production	

This datasheet has been download from:

www.datasheetcatalog.com

Datasheets for electronics components.